

<b>Notice of References Cited</b>	Application/Control No. 10/521,778		Applicant(s)/Patent Under Reexamination KOMIYA ET AL.	
	Examiner Mia M. Thomas		Art Unit 2624	Page 1 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,038,024	03-2000	Berner, Markus	356/326
*	B	US-6,359,680	03-2002	Rubbert, Rudger	356/3.06
*	C	US-6,264,470	07-2001	Jung et al.	433/29
*	D	US-6,307,629	10-2001	Jung et al.	356/419
*	E	US-6,358,047	03-2002	Lehmann, Maryann	433/26
*	F	US-6,362,888	03-2002	Jung et al.	356/419
*	G	US-6,381,017	04-2002	Jung et al.	356/419
*	H	US-6,414,750	07-2002	Jung et al.	356/73
*	I	US-6,417,917	07-2002	Jung et al.	356/73
*	J	US-6,540,513	04-2003	Berner et al.	433/26
*	K	US-6,570,654	05-2003	Jung et al.	356/419
*	L	US-6,750,971	06-2004	Overbeck et al.	356/405
*	M	US-6,832,913	12-2004	Lehmann, Maryann	433/26

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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<b>Notice of References Cited</b>	Application/Control No. 10/521,778		Applicant(s)/Patent Under Reexamination KOMIYA ET AL.	
	Examiner Mia M. Thomas		Art Unit 2624	Page 2 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,870,616	03-2005	Jung et al.	356/326
*	B	US-6,606,514	08-2003	Grass et al.	600/427
*	C	US-6,917,429	07-2005	Imura et al.	356/405
*	D	US-6,964,567	11-2005	Kerschbaumer et al.	433/26
*	E	US-7,006,126	02-2006	Kerschbaumer et al.	348/66
*	F	US-7,030,986	04-2006	Overbeck et al.	356/405
*	G	US-7,097,450	08-2006	Jung et al.	433/26
*	H	US-7,341,450	03-2008	Pye et al.	433/29
*	I	US-7,538,878	05-2009	Jung et al.	356/419
*	J	US-7,596,253	09-2009	Wong et al.	382/128
*	K	US-7,682,150	03-2010	Jung et al.	433/26
*	L	US-7,136,093	11-2006	Itoh et al.	348/207.11
*	M	US-7,490,294	02-2009	Okada, Shizue	715/762

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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	X	

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<b>Notice of References Cited</b>	Application/Control No. 10/521,778		Applicant(s)/Patent Under Reexamination KOMIYA ET AL.	
	Examiner Mia M. Thomas		Art Unit 2624	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,355,633	04-2008	Kurosawa et al.	348/211.8
*	B	US-7,255,558	08-2007	Babayoff et al.	433/29
*	C	US-7,184,150	02-2007	Quadling et al.	356/602
*	D	US-7,142,312	11-2006	Quadling et al.	356/602
*	E	US-2003/0011767	01-2003	Imura et al.	356/326
*	F	US-4,011,571	03-1977	Okuzawa, Yasutoshi	396/291
*	G	US-4,300,823	11-1981	Yamanaka et al.	396/106
*	H	US-4,959,679	09-1990	Yamamoto et al.	396/165
*	I	US-5,381,207	01-1995	Kazumi, Jirou	396/57
*	J	US-5,995,763	11-1999	Posa et al.	396/57
*	K	US-6,413,207	07-2002	Minami, Itsuji	600/109
*	L	US-6,454,437	09-2002	Kelly, William	362/246
*	M	US-6,807,297	10-2004	Tankovich et al.	382/162

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

#### NON-PATENT DOCUMENTS

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	W	
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<b>Notice of References Cited</b>	Application/Control No. 10/521,778		Applicant(s)/Patent Under Reexamination KOMIYA ET AL.	
	Examiner Mia M. Thomas		Art Unit 2624	Page 4 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,033,172	04-2006	Hansen et al.	433/29
*	B	US-7,106,511	09-2006	Grot et al.	359/566
*	C	US-7,106,958	09-2006	Kerschbaumer et al.	396/16
*	D	US-7,118,374	10-2006	Culp, Lee	433/26
*	E	US-2009/0102964	04-2009	Yuyama et al.	348/371
*	F	US-2002/0177751	11-2002	Ueno et al.	600/160
*	G	US-2002/0114505	08-2002	Mahon et al.	382/145
*	H	US-2002/0071124	06-2002	Schwarz, Peter	356/445
*	I	US-2002/0015933	02-2002	Berner et al.	433/26
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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